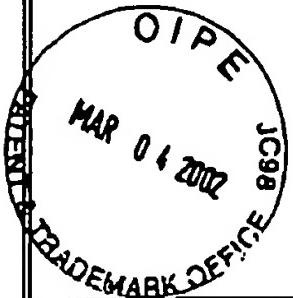


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(PTO-1449)

ATTY. DOCKET NO.
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September 28, 2001

GROUP

U.S. PATENT DOCUMENTS

EXAMINER'S INITIALS	PATENT NO.	DATE	NAME	CLASS	SUBCLASS	FILING DATE
WG	3894931	July 15, 1975	Nace et al.	-	-	
WG	3894933	July 15, 1975	Owen et al.	-	-	
WG	5098554	Mar. 24, 1992	Krishna et al.	-	-	
WG	4481104	Nov. 6, 1984	Walsh	-	-	
WG	4606810	Aug. 19, 1986	Krambeck et al.	-	-	
WG	4436613	Mar. 13, 1984	Sayles et al.	-	-	
WG	3928172	Dec. 23, 1975	Davis, Jr. et al.	-	-	
WG	4830728	May 16, 1989	Herbst et al.	-	-	
WG	5401387	Mar. 28, 1995	Harandi et al.	-	-	

FOREIGN PATENT DOCUMENTS

EXAMINER'S INITIALS	PATENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	Translation
						Yes No

OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)

EXAMINER	Walter W. Daff	DATE CONSIDERED
		5-4-2005

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EXAMINER'S INITIALS	PATENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
						Yes	No
WG	0142900	29.05.85	EPO	-	-		
WG	99/41331	19.08.99	WIPO	-	-		

OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)

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